

DOE-EERE Thermoelectric Applications Workshop
Thursday, Oct. 1st 2009

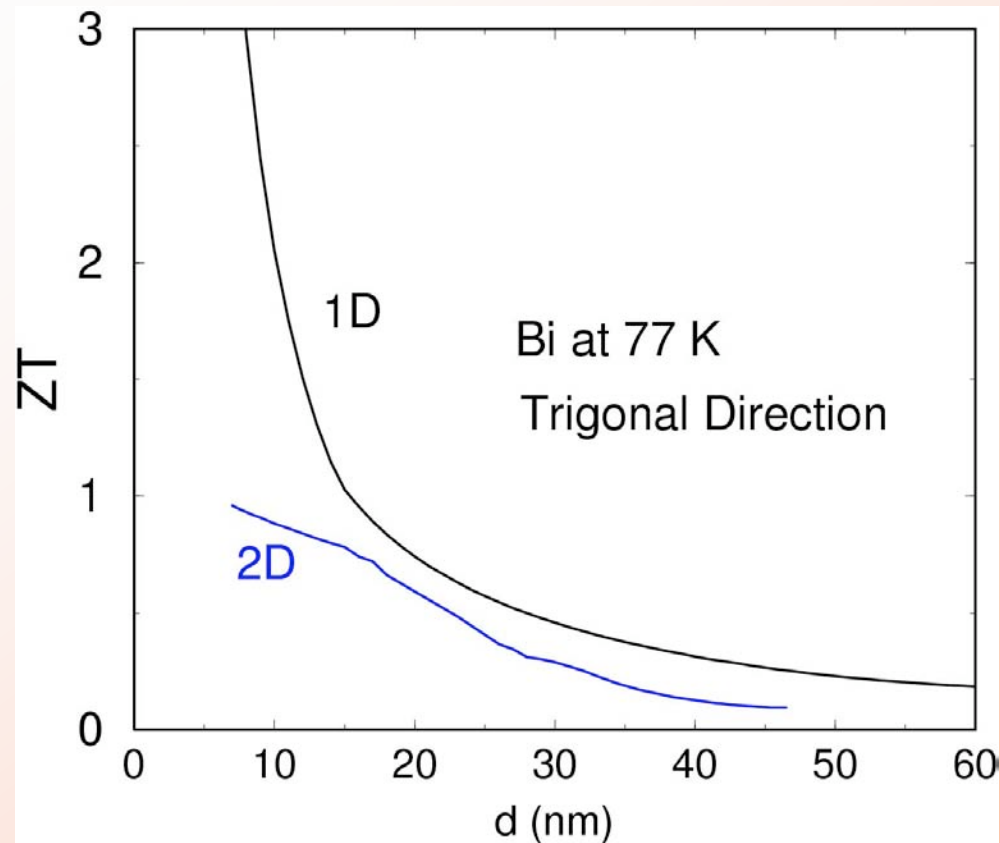
**Lattice Thermal Conductivity and Stability
of “TE Nano-Composites”**

Prof. Terry M. Tritt

email: ttritt@clemson.edu
<http://www.clemson.edu/caml/>

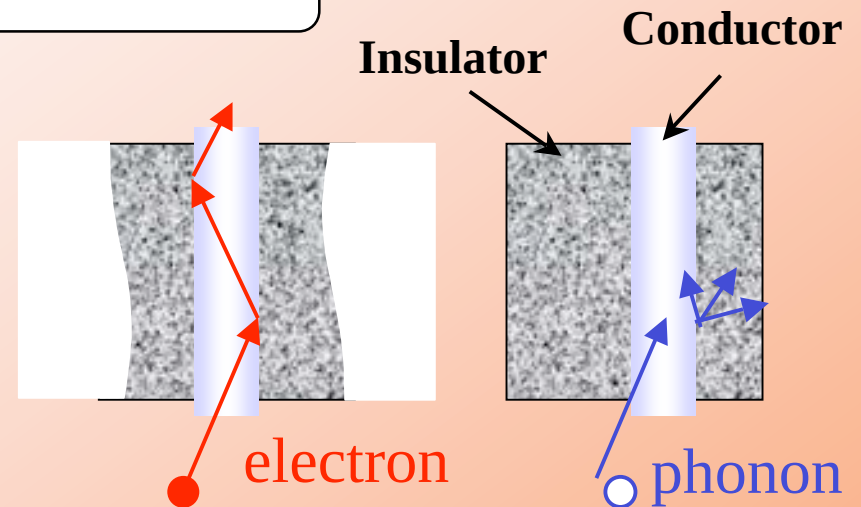
Dept. of Physics & Astronomy
Clemson University, Clemson, SC

Motivation for Low Dimensional TE Materials:



Hicks & Dresselhaus, PRB 1993

Dresselhaus, Plenary Talk - ICT 05, Adv. Mats 07



Quantum Enhancement

Increase Seebeck

Interface Scattering
Large Kapitza Resistance

Reduce κ_L



Relative Importance of α^2/ρ and κ

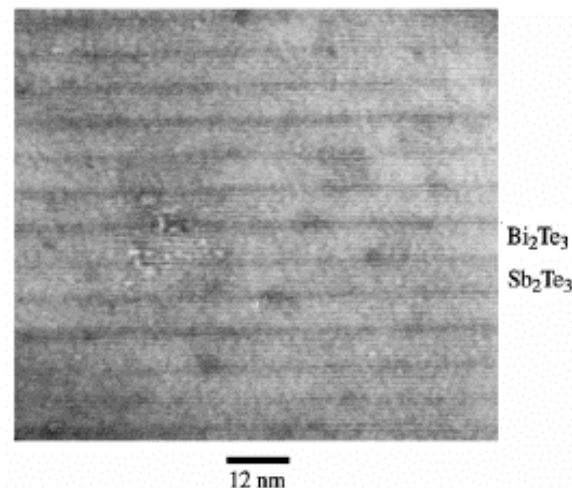
$\text{Bi}_2\text{Te}_3 / \text{Sb}_2\text{Te}_3$	Nano	Bulk
α^2/ρ ($\mu\text{W}/\text{cm}\cdot\text{K}^2$)	40	51
κ ($\text{W}\cdot\text{m}^{-1}\text{K}^{-1}$)	0.6	1.45
ZT (T = 300K)	2.4	1.0

Venkatasubramanian et.al., Nature 413, 597, 2001

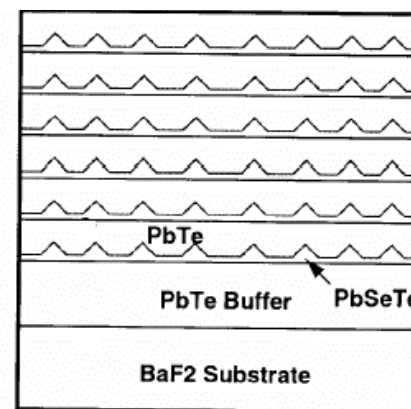
PbTe/PbSeTe	Nano	Bulk
α^2/ρ ($\mu\text{W}/\text{cm}\cdot\text{K}^2$)	32	28
κ ($\text{W}\cdot\text{m}^{-1}\text{K}^{-1}$)	0.6	2.5
ZT (T = 300K)	1.6	0.3

T. Harman et.al, Science, 297, 2229 (2002)

$\text{Bi}_2\text{Te}_3/\text{Sb}_2\text{Te}_3$ Superlattice



PbTe/PbSeTe Quantum Dots



$\text{PbSe}_x\text{Te}_{1-x}$ quantum dots in PbTe layers



Relative Importance of α^2/ρ and κ

Thermal Conductivity Reduction

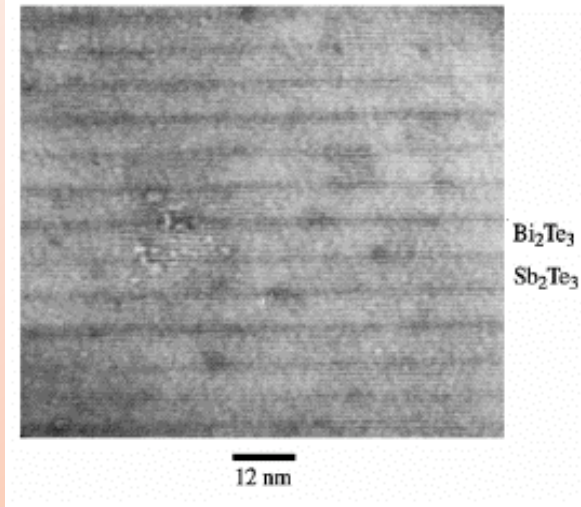
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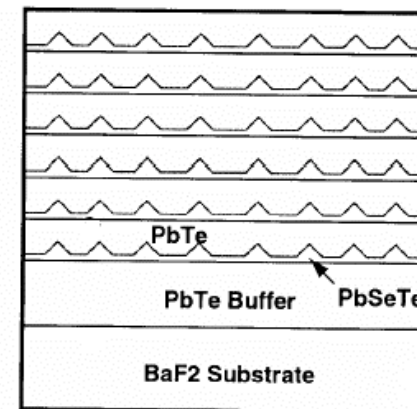
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$\text{Bi}_2\text{Te}_3/\text{Sb}_2\text{Te}_3$ Superlattice



PbTe/PbSeTe Quantum Dots

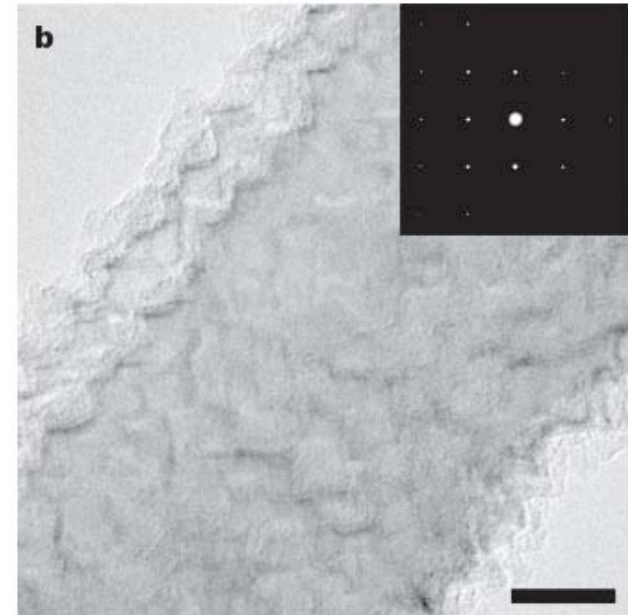
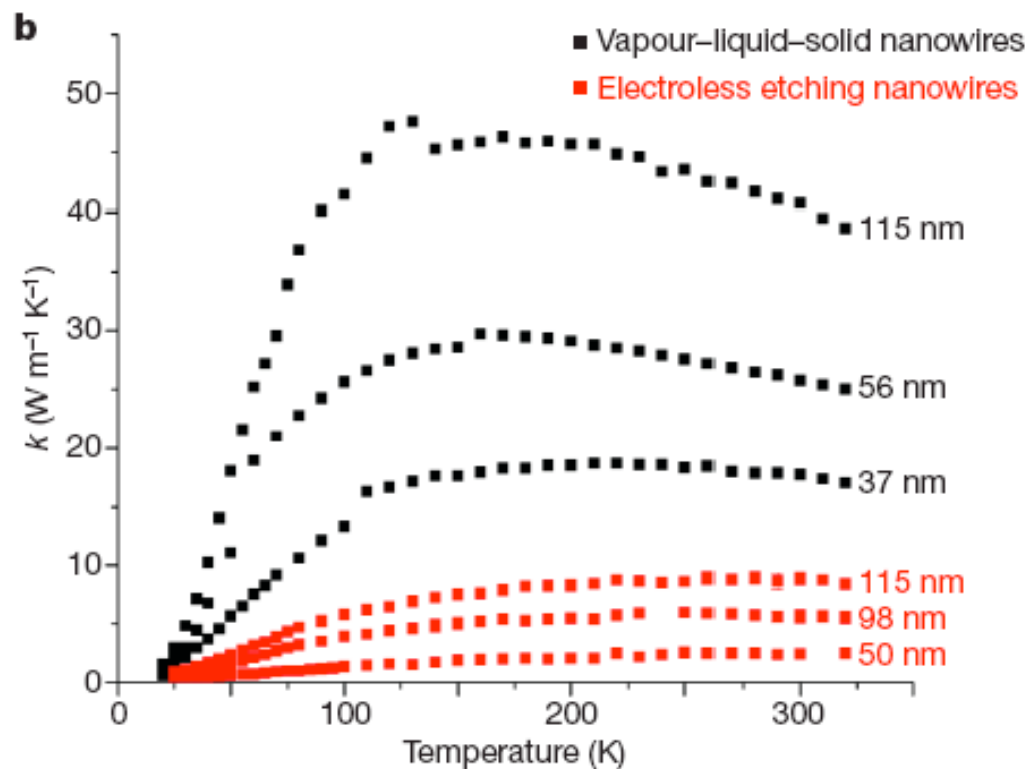


$\text{PbSe}_x\text{Te}_{1-x}$ quantum dots in PbTe layers



TE Enhancement of Roughened Si Nanowires

A. Hochbaum et.al., Nature, 451-p 163 (2008)
Jan 2008 -- LBNL & Berkeley Groups



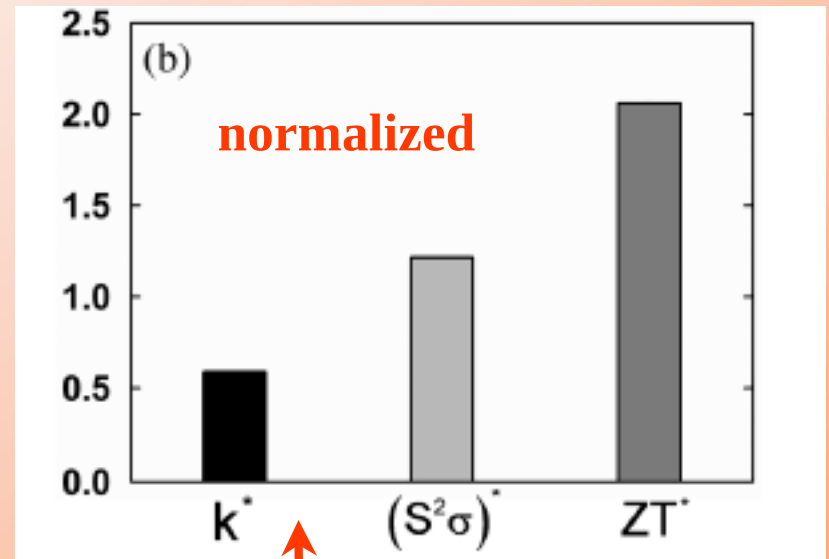
Surface Roughness Above
Leads to Reduction in
Thermal Conductivity (Left)

Embedding Nanoparticles in Crystalline Semiconductors

ErAs nanoparticles in $\text{In}_{0.53}\text{Ga}_{0.47}\text{As}$ matrix
Epitaxial growth
Goal to “Beat the Alloy Limit”
Uncorrelated Phonon Scattering

W. Kim et.al., PRL, 96-045901 (2006)
Santa Cruz & Berkeley Groups

- Reduction in κ_L (“nano- phonon effect”)
Depends on ML thickness (ErAs nano)*
- Power Factor about same
but ErAs can act as a dopant
- ZT significantly enhanced
- Theoretical analysis showed that
 - ErAs nanoparticles scatter
mid to long λ phonons*
 - While atomic scale defects scatter
short λ phonons.



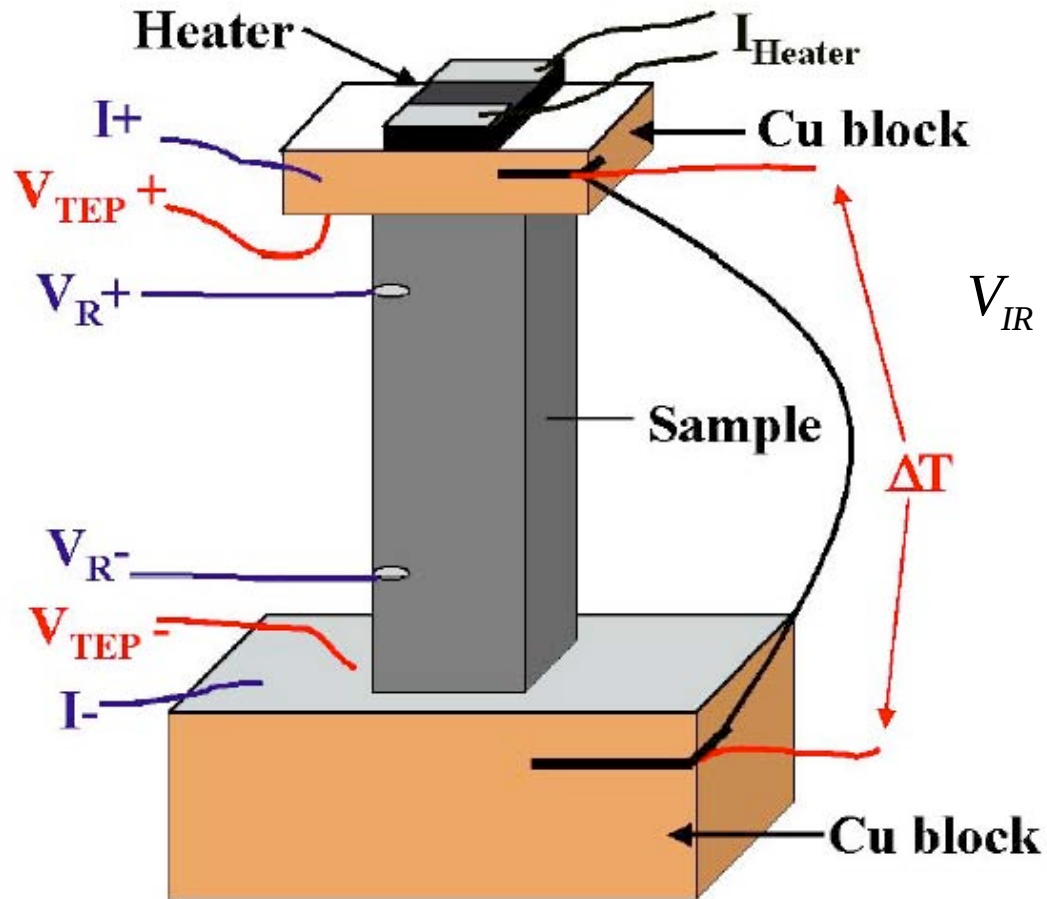
κ_L reduced a factor of 2
below the alloy limit!
ZT enhanced a factor of 2 !



*TE Nanomaterials Growth,
TE Nanocomposites &
Grain Boundary Engineering*

*But First,
Discussion on TE Measurements!*

Resistivity and Seebeck Measurement Description:



Measure all Properties on Same Sample!

$$V_{Total} = V_{IR} + V_{TE}^*$$

$$V_{IR} = \frac{[V(I^+) + V_{TE}^*] - [V(I^-) + V_{TE}^*]}{2}$$

$$\alpha_{AB} = \frac{\Delta V}{\Delta T} = \frac{(V_H - V_L)}{(T_H - T_L)}.$$

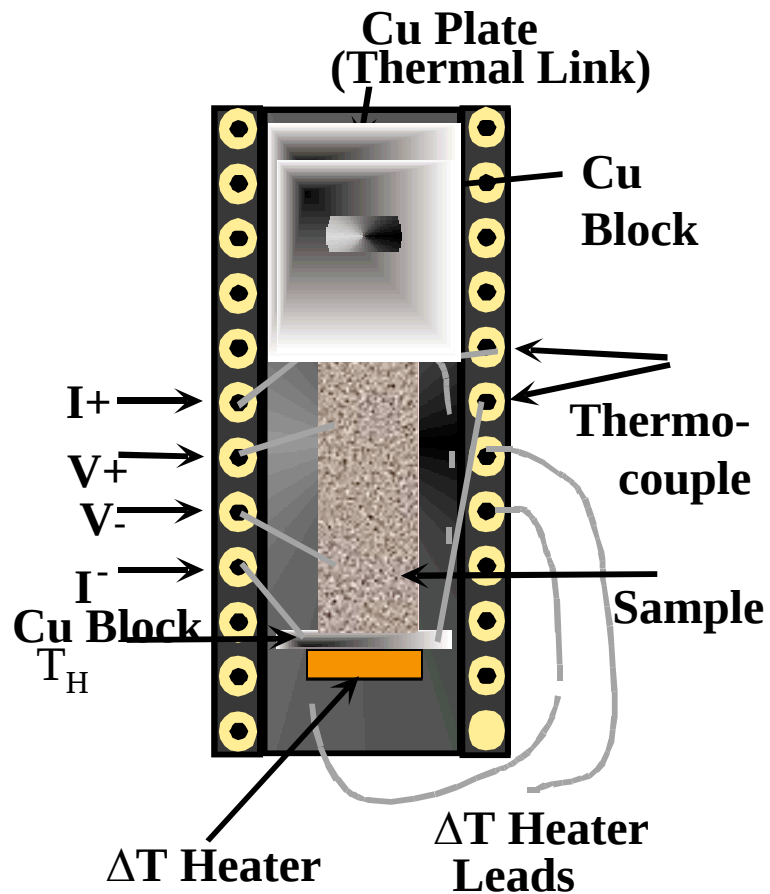
Important to measure ΔT Correctly where ΔV_{TE} is measured

Cryocooler Head for R & α Measurements System (3 Systems):

Typical Size: $2 \times 2 \times 8 \text{ mm}^3$

$6\text{-}10\text{K} < T < 320 \text{ K}$

**Measures
two samples
Simultaneously
 $6 \text{ K} < T < 320 \text{ K}$**

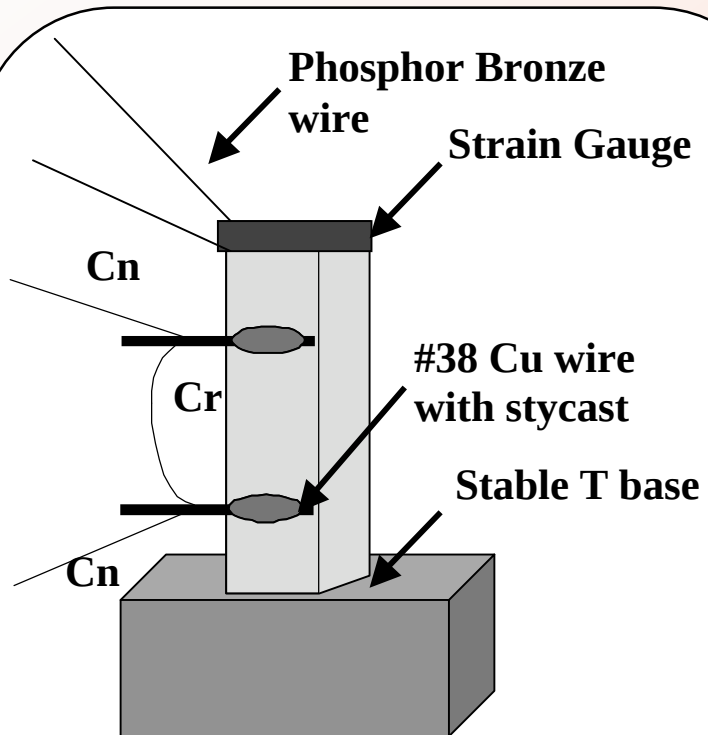


**IC Chip
receptacle**

•A. L. Pope, R. T. Littleton, IV and **Terry M. Tritt**, Rev. Sci. Instrum., **72**, 3129 (2001)



Thermal Conductivity -Bulk Samples



$$\kappa = \frac{P_s L}{A \Delta T}; P_s = I^2 R - P_{loss}$$

Pope et.al Cryogenics, **41**, 725 (2001)

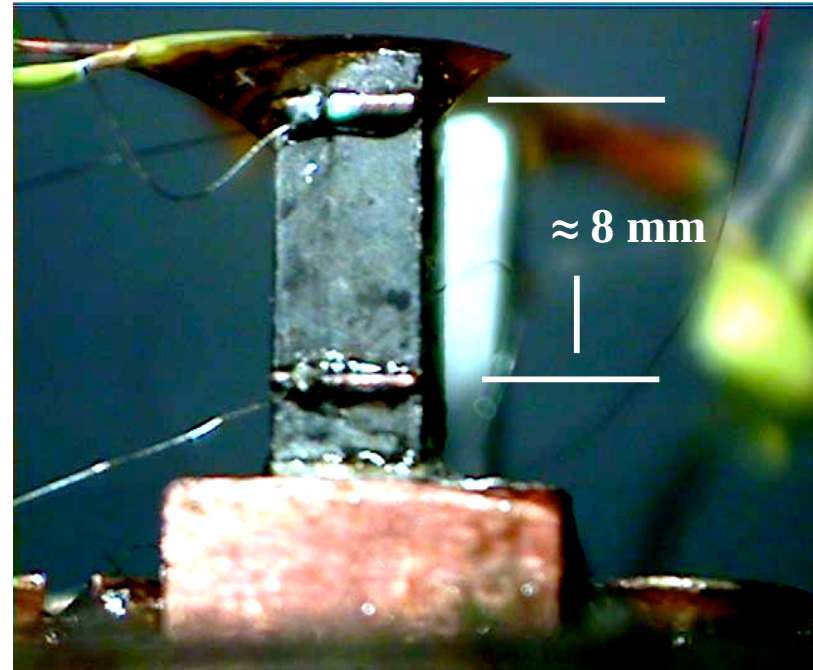
Low Temp Thermal Conductivity:

Steady State Method

(6K to 320 K)

P vs. ΔT Sweeps @ Constant T

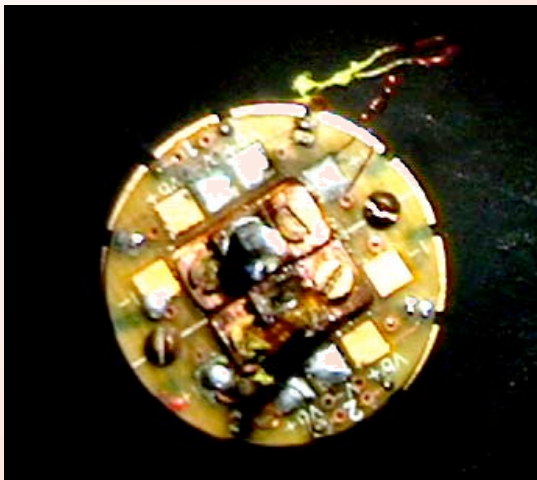
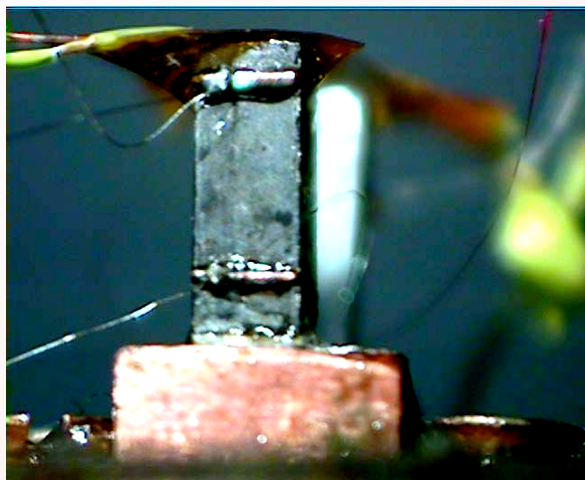
$$P_{Sam} = \kappa_{Tot} \frac{A}{L_s} \Delta T$$



Sample Width $\approx 3\text{mm}$



Thermal Conductivity -Bulk Samples



Absolute steady state technique

Two samples may be mounted simultaneously

Dismountable puck

The puck socket attached on a Cryocooler

Three Separate Systems

Thermal conductivity measured from 6 K to 300 K

A. L. Pope, B. M. Zawilski and Terry M. Tritt
Cryogenics, **41**, 725 (2001)



High Temp Thermal Conductivity:

High Temperature DSC
Measure C_p To 1500°C
Thermal Stability & Heat Capacity



NETZSCH LFA 457
Thermal Diffusivity (d)
Or Conductivity (κ)
Temp Range: RT to 1100°C

$$\kappa = d\rho_D C_V$$



Schematic of the flash method

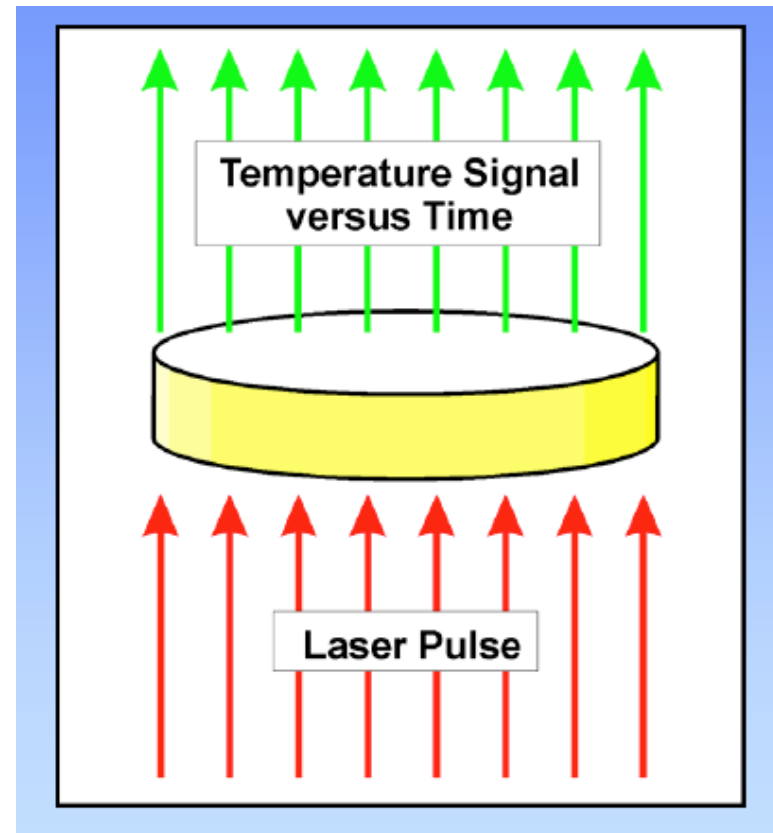
$$\kappa = d\rho_D C_V$$

κ = thermal conductivity

d = thermal diffusivity

ρ_D = density

C_V = Heat Capacity



Temperature increase for various experimental conditions

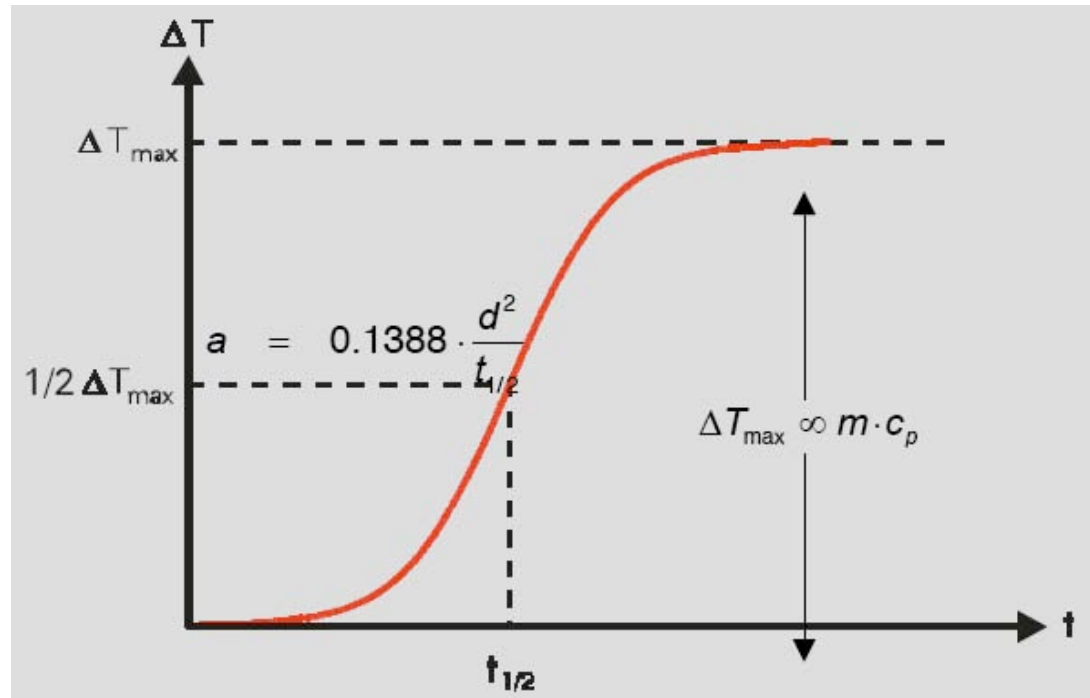
$$d = 0.1388 \left(\frac{L^2}{t_{1/2}} \right)$$

$t_{1/2}$ = Rise half time

d = thermal diffusivity

L = sample thickness

assumes ideal conditions of
adiabatic sample and
instantaneous pulse heating



$$\kappa = d \rho_D C_V$$

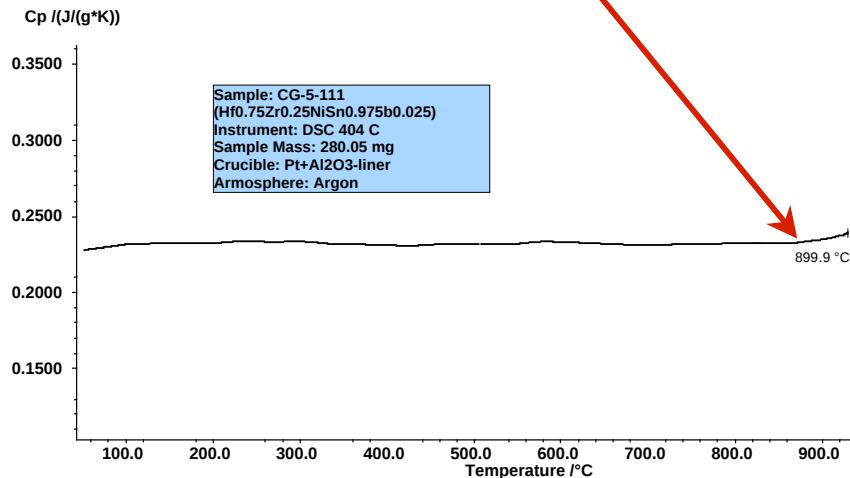
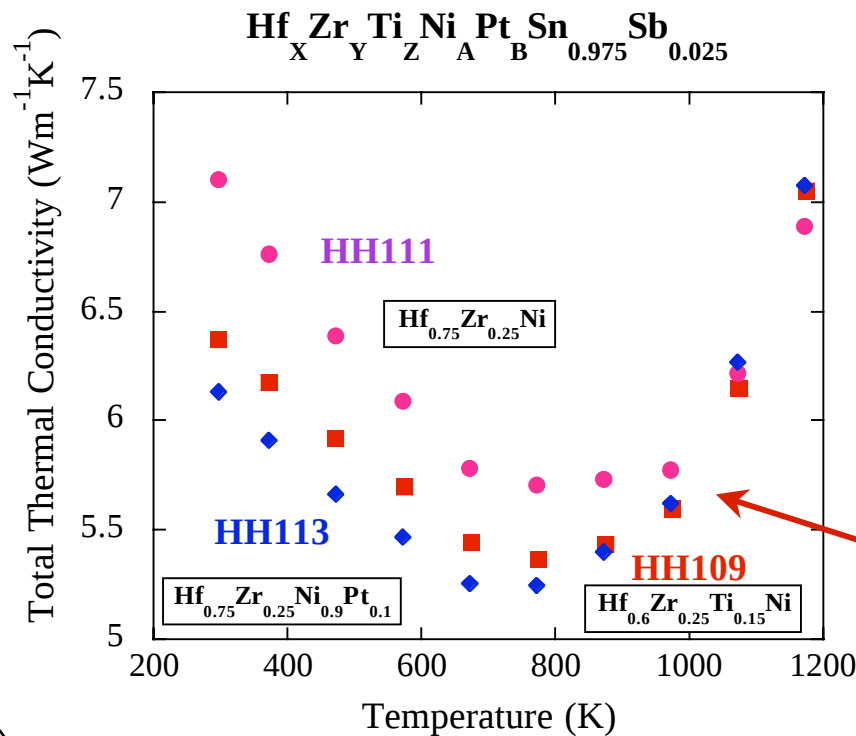
J. W. Parker et.al., J. Appl. Phys., 32, 1679 (1961)



Thermal Analysis Systems:

High Temp DSC in conjunction with Laser Flash
--- Shows Thermal Stability of Half Heusler Alloys to 900°C

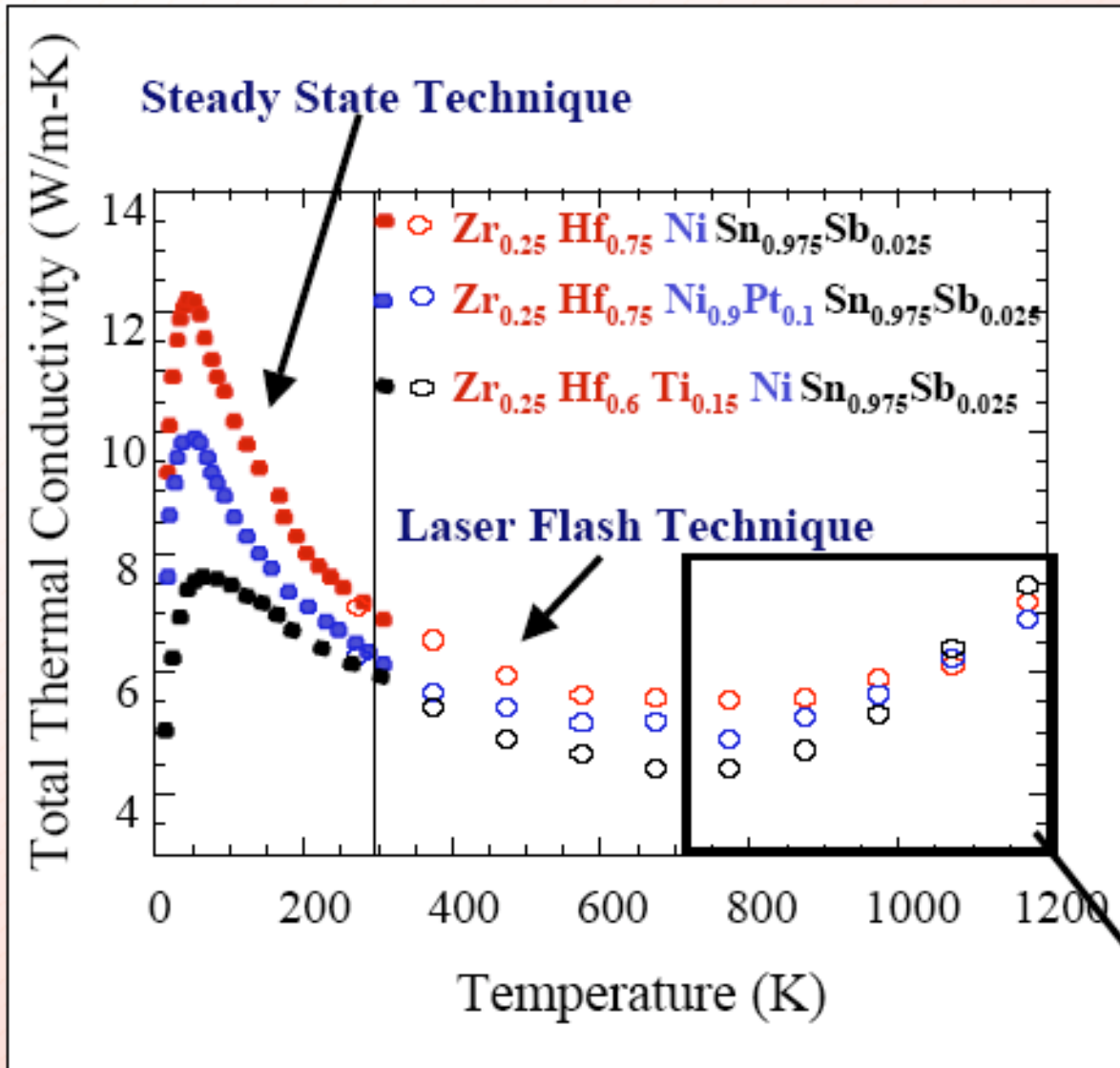
UVA & Clemson Results



S. Culp, S. J. Poon & T. M. Tritt: APL, 2006

Derived Thermal Conductivity
Half Heusler Alloys to 900°C





Good Agreement
From the Two Systems

Very Different
Techniques

Two Carrier Heat
Conduction



Acquisition of Commercial High Temperature R & α System

Thermal Analysis/Thermal Measurement
ULVAC-RIKO, INC.
Seebeck Coefficient
and Electric Resistance
Measuring System **ZEM-2 Series**



**Commercial
High Temperature
R & α System**

25°C to 800°C

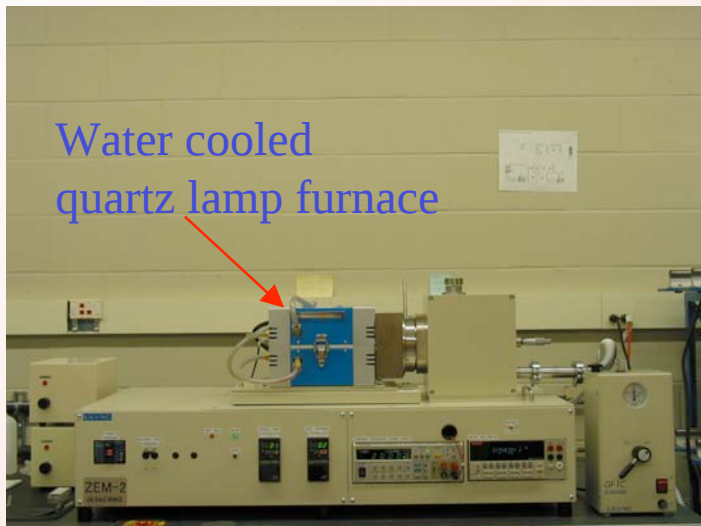
Automated

Enhanced Through put

Less Down Time

ULVAC (ZEM-2)

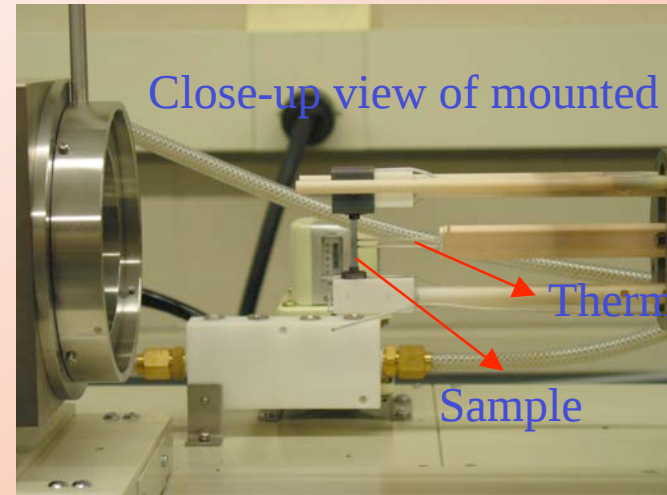
Commercial high temp.R & S system



Water cooled
quartz lamp furnace



Open position showing sample
& thermocouples



Close-up view of mounted sample

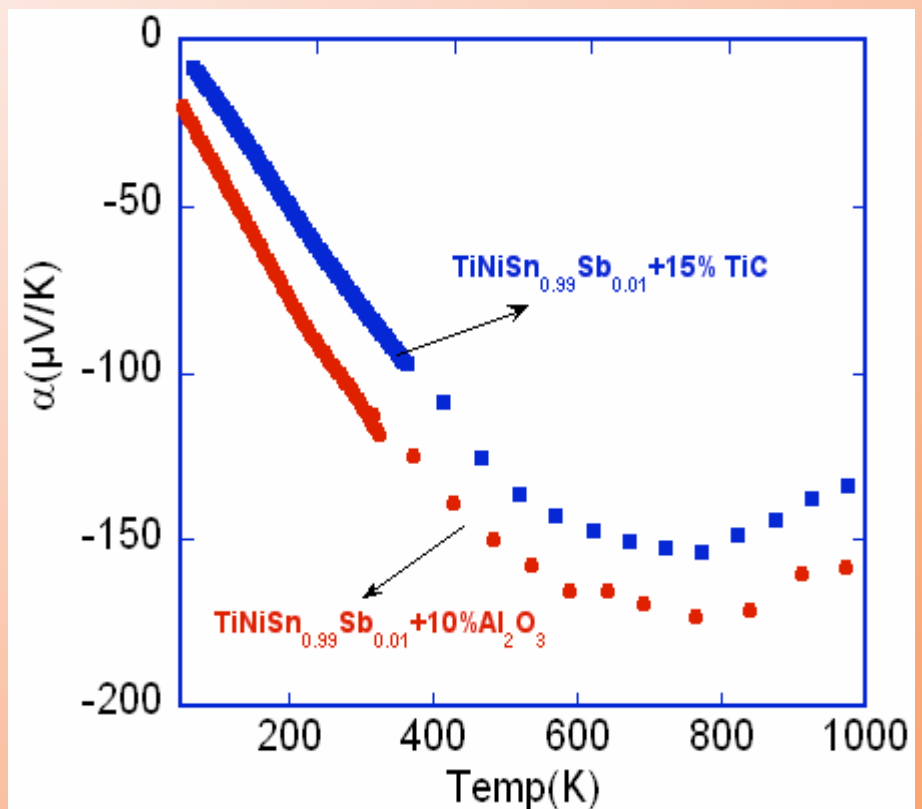
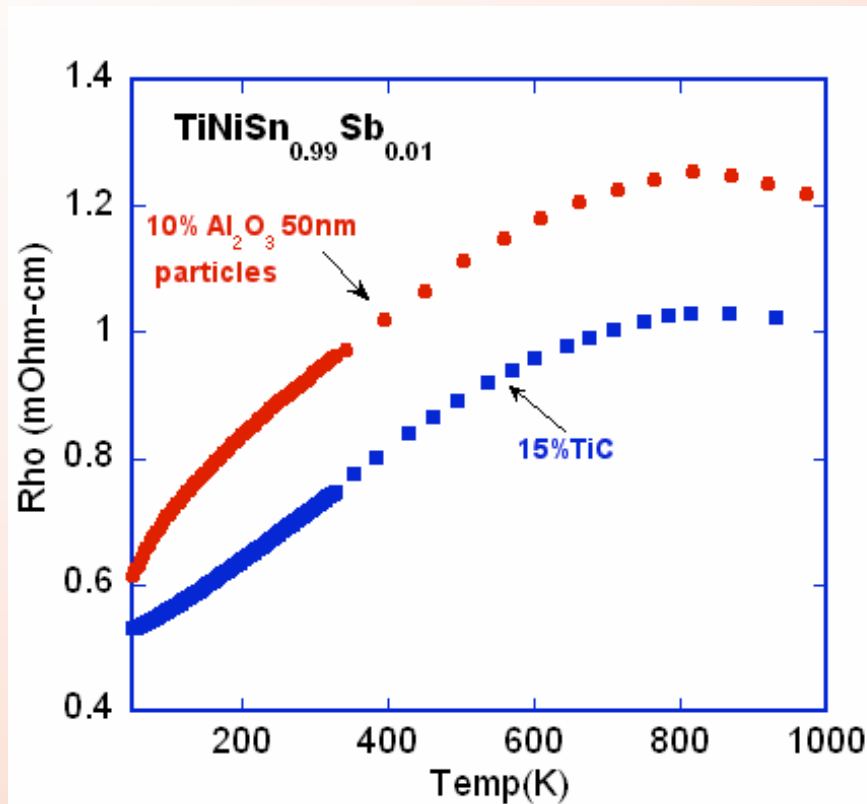
Thermocouples

Sample

- Temp. range:- 30 to 800°C
- Sample size: 2mm x 2mm x 7mm min.
- Both rod & bar samples can be mounted
- R & S data collected simultaneously
- Completely automated system
- Design allows rapid data collection

See also- V. Ponnalbalam et. al., Rev. Sci Instrum., 2006

R & S data of $\text{TiNiSn}_{0.99}\text{Sb}_{0.01}$ nano-composites



Data collected using both low temp. setup and ULVAC (ZEM-2) high temp. system
Data matched well at RT

Elementary Error Propagation

$$Q = Q(a, b, c)$$

$$\delta Q = \frac{\partial Q}{\partial a} \delta a + \frac{\partial Q}{\partial b} \delta b + \frac{\partial Q}{\partial c} \delta c$$

$$\frac{\delta Q}{Q} = \frac{\delta a}{a} + \frac{\delta b}{b} + \frac{\delta c}{c}$$

$$ZT = \frac{\alpha^2 \sigma T}{\kappa} = \frac{\alpha^2 \sigma T}{\kappa_E + \kappa_L} = \frac{\alpha^2 T}{\rho \kappa}$$

$$\frac{\delta ZT}{ZT} = 2 \frac{\delta \alpha}{\alpha} + \frac{\delta T}{T} + \frac{\delta \rho}{\rho} + \frac{\delta \kappa}{\kappa}$$

$$\kappa = K \frac{L_{TC}}{A}$$

$$\rho = R \frac{A}{L_V}$$

$$\frac{\delta \rho}{\rho} = \frac{\delta R}{R} + \frac{\delta w}{w} + \frac{\delta t}{t} + \frac{\delta L_V}{L_V}$$



High Temp Measurements
 $d - (\kappa)$ by Laser Flash
& DSC (C_p)

$$\kappa = d \rho_D C_V$$

$$ZT = \frac{\alpha^2 \sigma T}{\kappa} = \frac{\alpha^2 \sigma T}{\kappa_E + \kappa_L} = \frac{\alpha^2 T}{\rho \kappa}$$

Measure all on One Sample

Low Temp Measurements
 $K - (\kappa)$ by Steady State

$$P = K \Delta T = I^2 R - P_{Loss}$$

$$\kappa = K \frac{L_{TC}}{A}$$

$$\rho = R \frac{A}{L_V}$$



High Temp Measurements
 $d - (\kappa)$ by Laser Flash
 & DSC (C_p)

$$\kappa = d \rho_D C_V$$

Low Temp Measurements
 $K - (\kappa)$ by Steady State

$$P = K \Delta T = I^2 R - P_{Loss}$$

$$ZT = \frac{\alpha^2 \sigma T}{\kappa} = \frac{\alpha^2 \sigma T}{\kappa_E + \kappa_L} = \frac{\alpha^2 T}{\rho \kappa}$$

$$\kappa = K \frac{L_{TC}}{A}$$

$$ZT = \frac{\alpha^2 T}{\rho \kappa} = \frac{\alpha^2 T}{R \left(\frac{A}{L_V} \right) K \left(\frac{L_{TC}}{A} \right)}$$

$$\rho = R \frac{A}{L_V}$$

At best $\approx 5-7\%$ uncertainty on ZT!

Same Sample -- A cancels

*TE Nanomaterials Growth,
TE Nanocomposites &
Grain Boundary Engineering*

Summary Slide Highlights

Expanded Version at End

Various TE Materials Research @ Clemson:

Skutterudites:

Double-filled $\text{In}_x\text{Yb}_y\text{Co}_4\text{Sb}_{12}$ Skutterudites; J. Peng et.al.

Jour. of Appl. Phys., **105**, 084907 (2009);

Jour. of Appl. Phys., **104**, 053710 (2008)

$\text{La}_{0.9}\text{CoFe}_3\text{Sb}_{12}$ - CoSb_3 Skutterudite Nanocomposites, P.Alboni, et.al.

Jour. of Appl. Phys., **103**, 113707, (2008)

Half Heusler Alloys:

(Zr,Hf)Co(Sb,Sn) half-Heusler phases as p-type thermoelectric materials

Slade R. Culp et.al. Appl. Phys Letters, **93**, 022105 (2008)

Boundary scattering on the thermal conductivity of TiNiSn-based HH alloys,

S. Bhattacharya, et.al. Phys. Rev. B, **77**, 184203 (2008)

Oxide TE Mats:

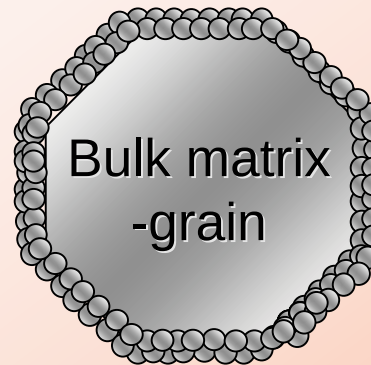
In-plane thermal conductivity of $\text{Na}_x\text{Co}_2\text{O}_4$ single crystals

Xiaofeng Tang et. al. Phys. Stat. Sol. A, **205** (5), 1152 (2008)



Nanocomposites fabricated by Hydrothermal /solvothermal nano-planting/coating

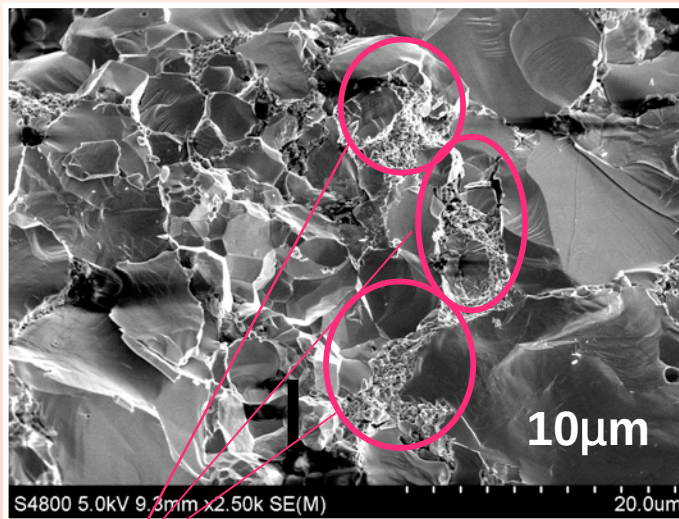
- o Nanoparticles are easy to form aggregates.
- o In TE nanocomposites, inhomogeneity may debase the TE performance.



Hot press

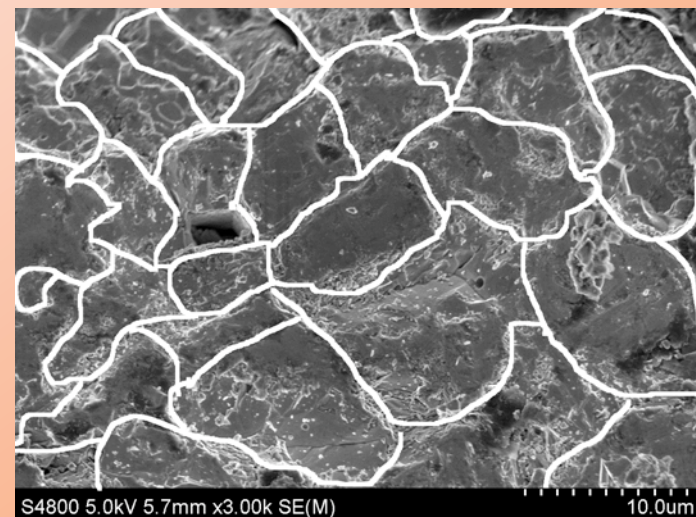
Relatively-homogeneous nanocomposite

Mechanical mixing



Nanoparticle-clusters

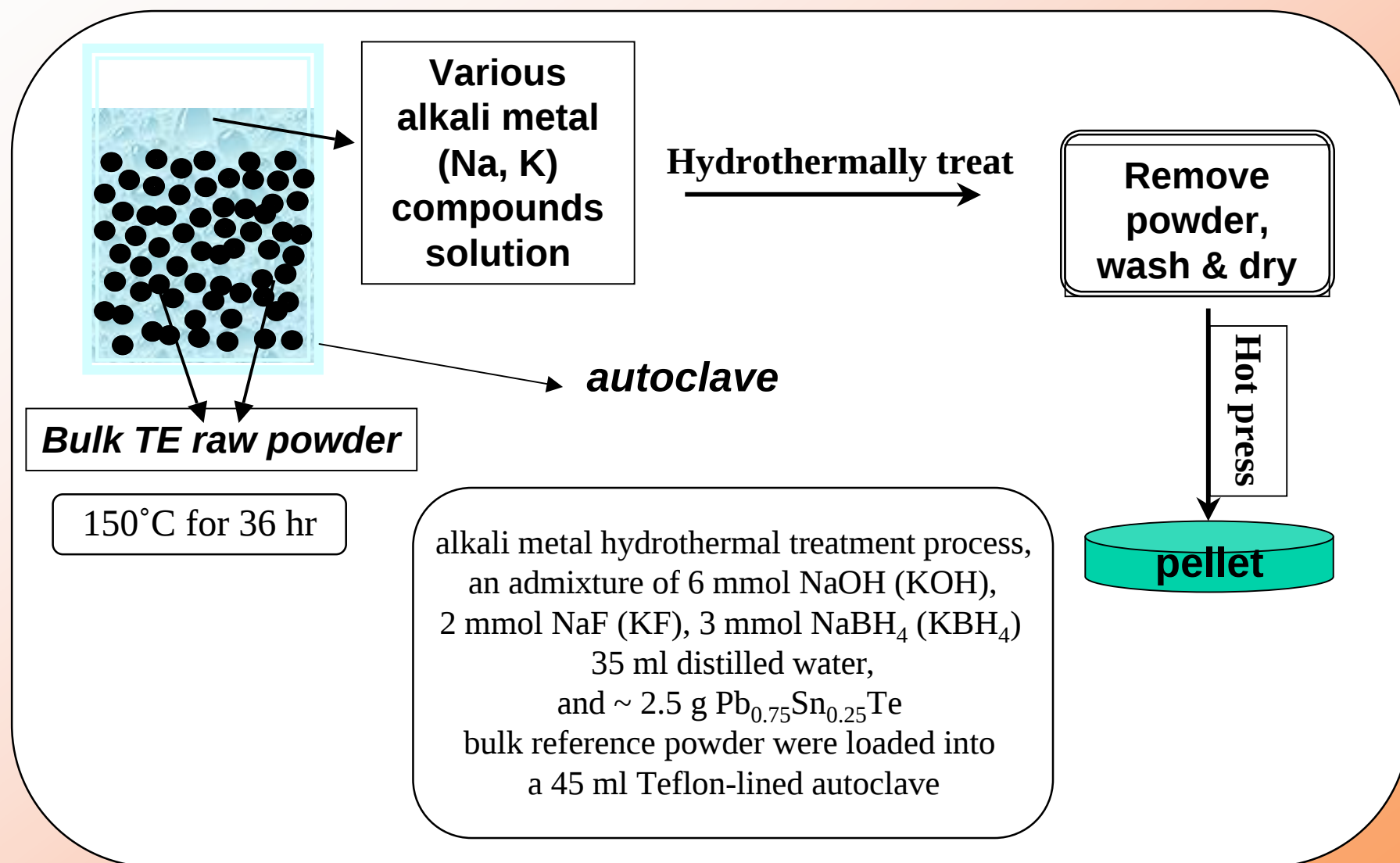
Solvothermal nano-coating



Better homogenous distribution of Nanostructures



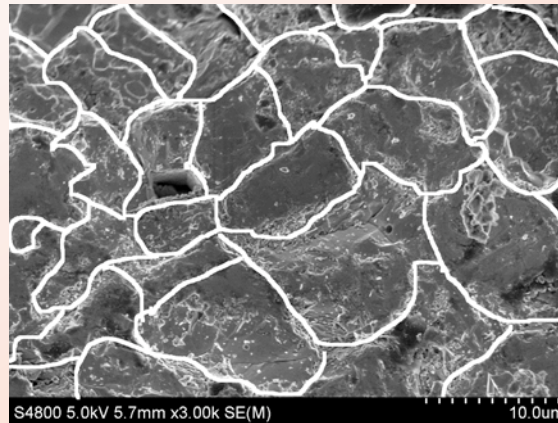
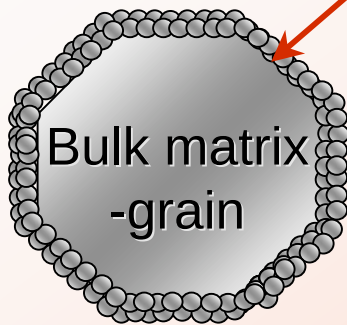
An alkali metal hydrothermal treatment technique



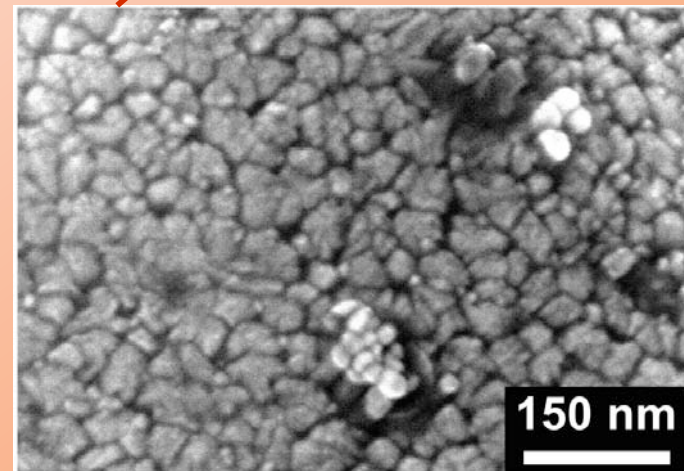
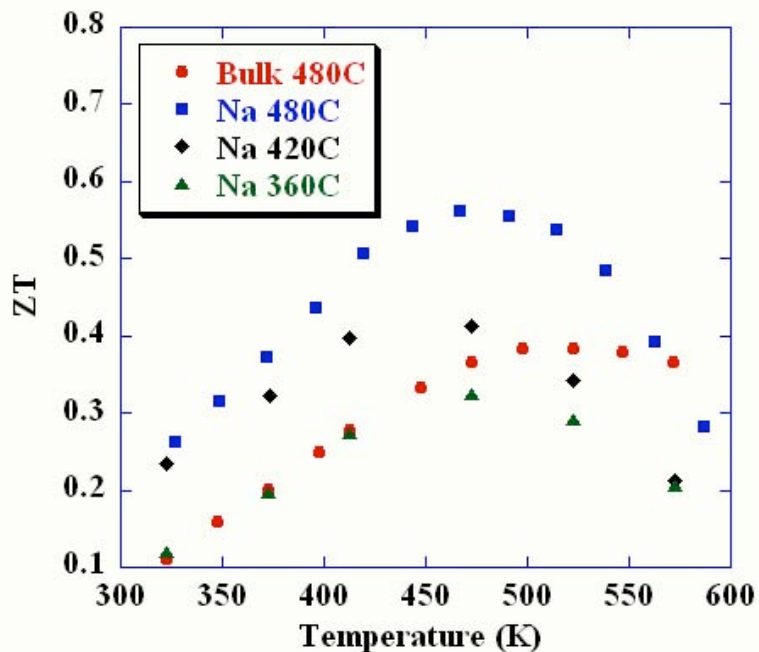
Hydrothermal Treatment of $\text{Pb}_{0.75}\text{Sn}_{0.25}\text{Te}$

Hydrothermal Treat with NaOH

X. Ji. *et.al.*, Phys-Stat-Sol-a-**206**, 221 (2009)



Observe 20-50 nm Clusters
On Surface of $\text{Pb}_{0.75}\text{Sn}_{0.25}\text{Te}$
Hot Pressed to $T > 400^\circ\text{C}$
(Te rich interface)



Hydrothermal Treatment of $\text{Pb}_{0.75}\text{Sn}_{0.25}\text{Te}$

X. Ji. *et.al.*, Phys-Stat-Sol-a-**206**, 221 (2009)

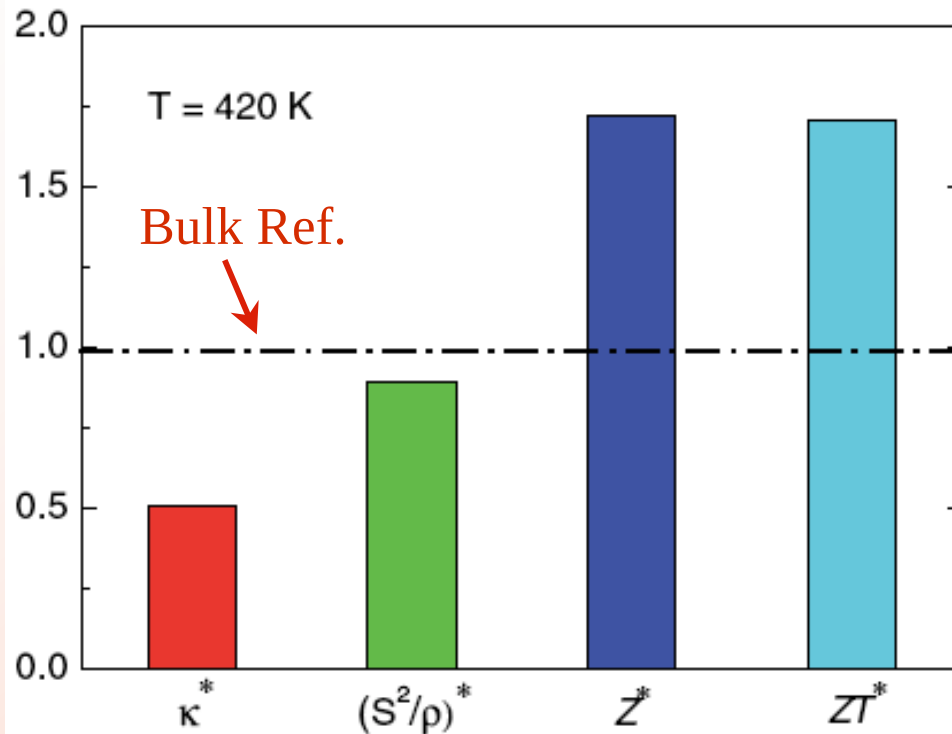


Figure 5 (online colour at: www.pss-a.com) Resulting enhancement of thermoelectric figure of merit at 420 K. Thermal conductivity, power factor, and thermoelectric figures of merit Z and ZT of Na solution hydrothermally treated $\text{Pb}_{0.75}\text{Sn}_{0.25}\text{Te}$ are normalized by the corresponding values of the bulk reference $\text{Pb}_{0.75}\text{Sn}_{0.25}\text{Te}$. The dash-dotted line shows where the bulk reference is. It is clear that the increases of Z and ZT are due to

Normalized Properties

Dashed Line -- Bulk reference

Enhancements in ZT
Due to Reduction
in κ_L !



Novel Nanostructures and High ZT in Melt Spun p-type $\text{Bi}_{0.52}\text{Sb}_{1.48}\text{Te}_3$

Collaboration with Prof. X. Tang and student Wenjie Xie
Wuhan Univ. of Tech:

W.Xie *et.al*, Applied Phys Letters, **94**, 102111-09

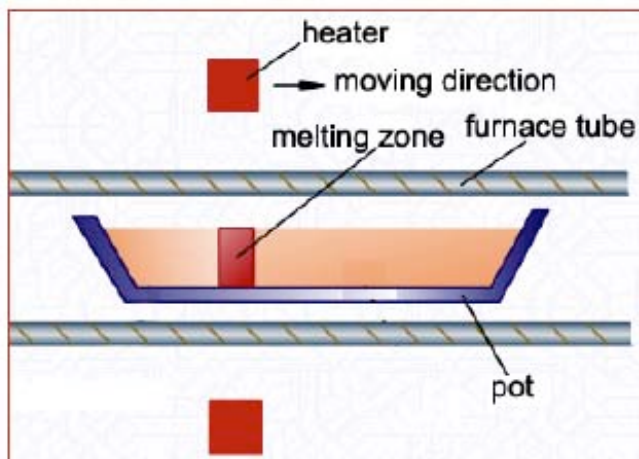
Also Jour. Appl. Phys., 2009

Supported by China Scholarship Program,
973 Programs and China NSF
US Dept. of Energy EPSCoR

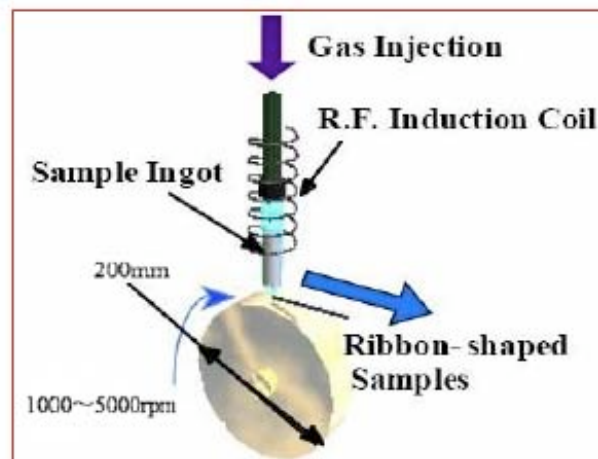


Novel Nanostructures in Melt Spun p-type $\text{Bi}_{0.52}\text{Sb}_{1.48}\text{Te}_3$

Zone Melted Ingot



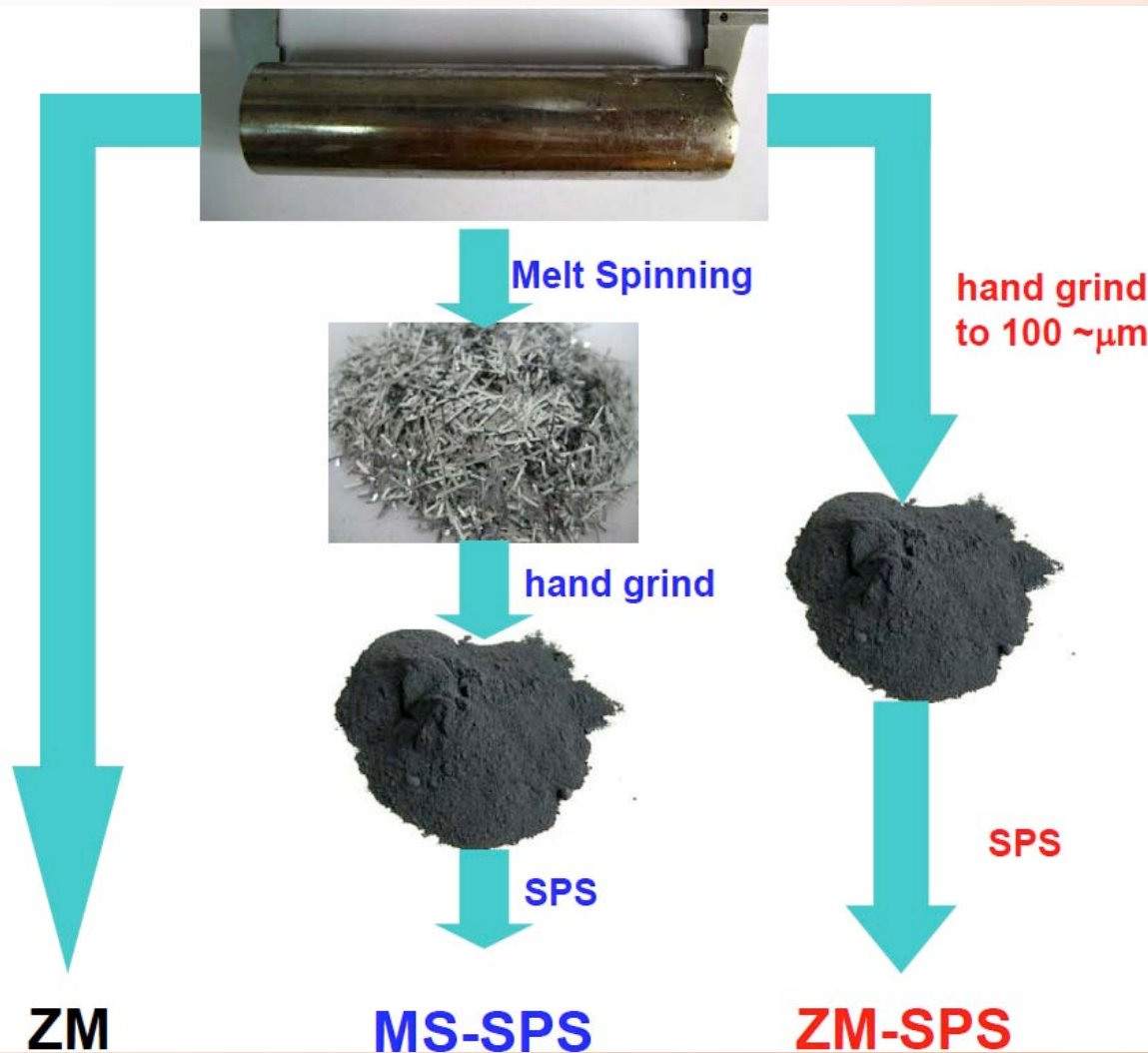
Melt Spun Ribbons



Collaboration w. Prof. X. Tang and student Wenjie Xie
Wuhan Univ. of Tech:

W.Xie *et.al*, Applied Phys Letters, **94**, 102111-2009

Novel Nanostructures in Melt Spun p-type $\text{Bi}_{0.52}\text{Sb}_{1.48}\text{Te}_3$



Spark Plasma
Sintering Conditions

300- 400 °C
For several minutes

Force $\approx$ 3-5 KN

Collaboration w. Prof. X. Tang and student Wenjie Xie
Wuhan Univ. of Tech:

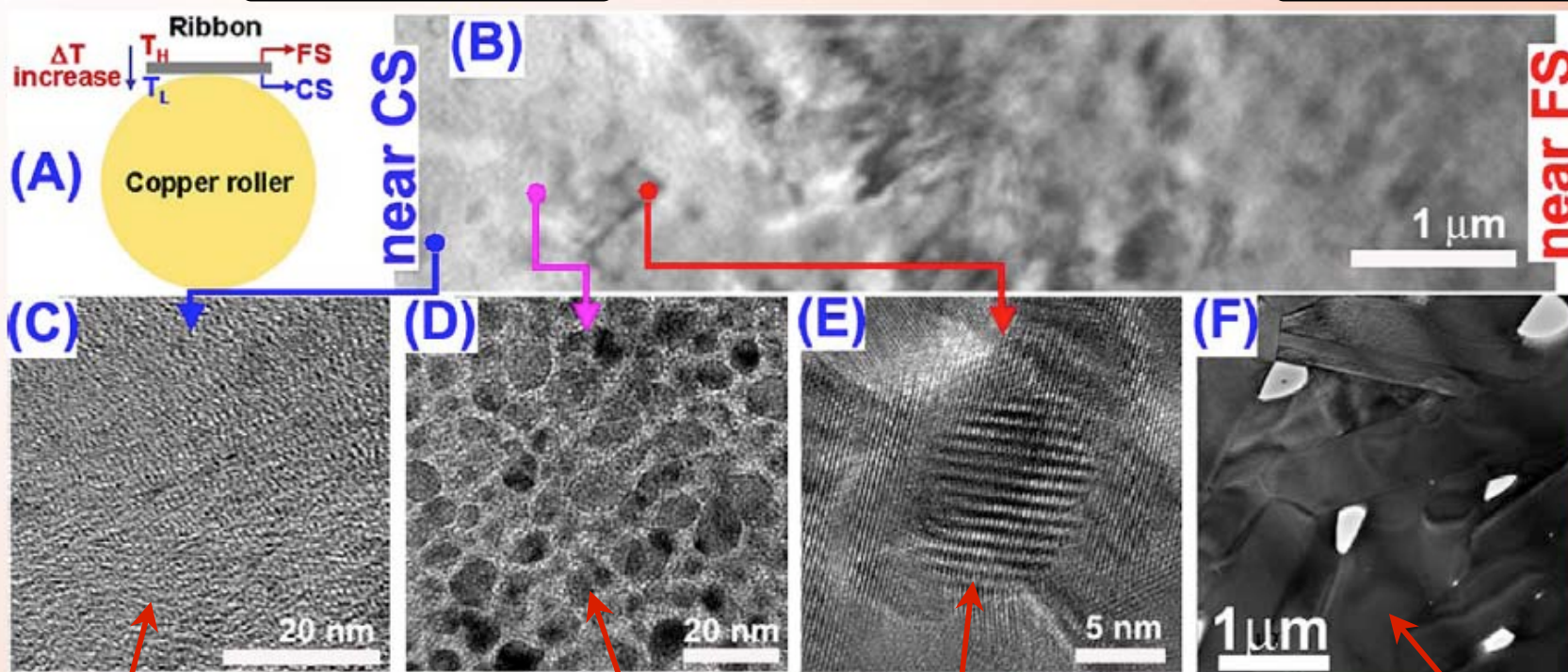
W.Xie *et.al*, Applied Phys Letters, **94**, 102111-2009



Novel Nanostructures in Melt Spun p-type $\text{Bi}_{0.52}\text{Sb}_{1.48}\text{Te}_3$

Contact Surface

Free Surface



Amorphous
Microstructure near
Contact surface

5-15 nm Nanocrystalline
Regions or grains near CS

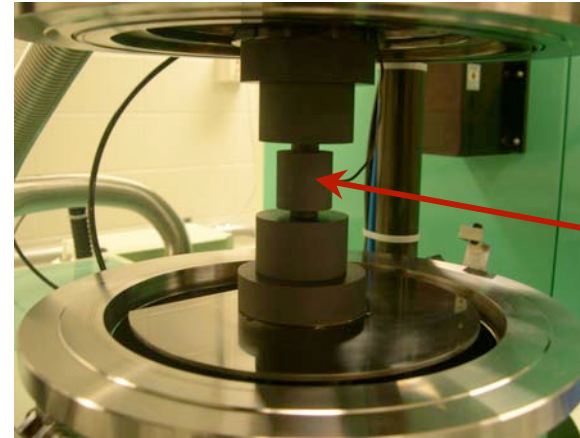
Large dendritic
regions near
free surface

Collaboration w. Prof. X. Tang and student Wenjie Xie
Wuhan Univ. of Tech:

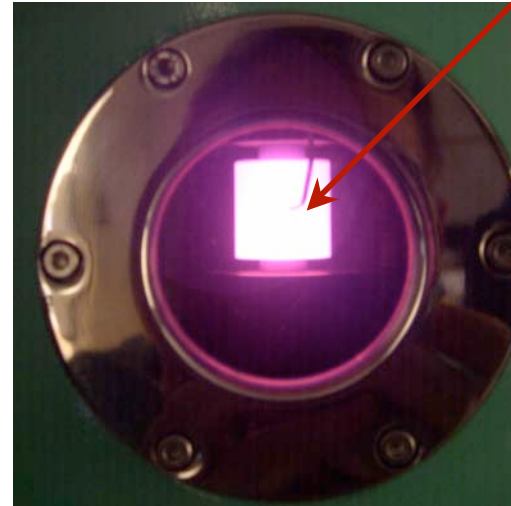
W.Xie *et.al*, Applied Phys Letters, **94**, 102111-2009



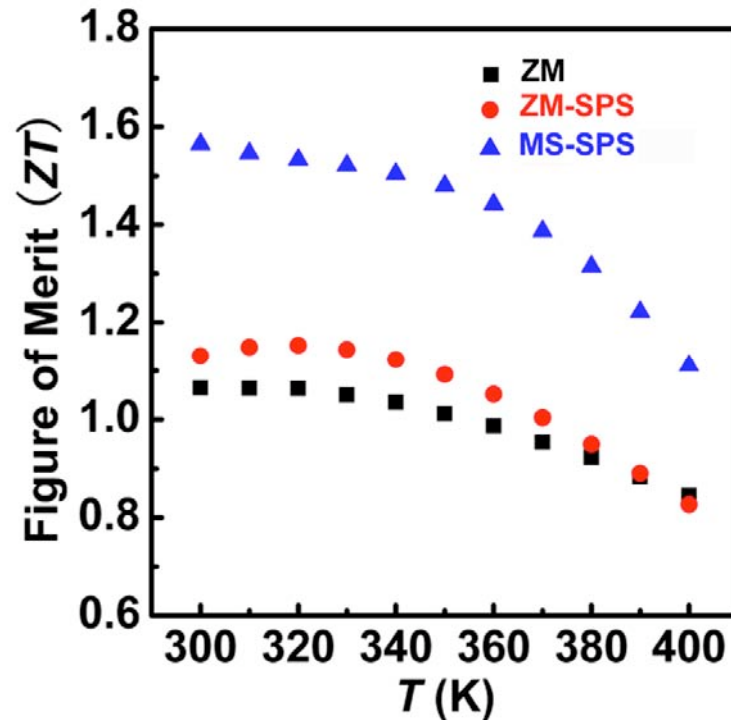
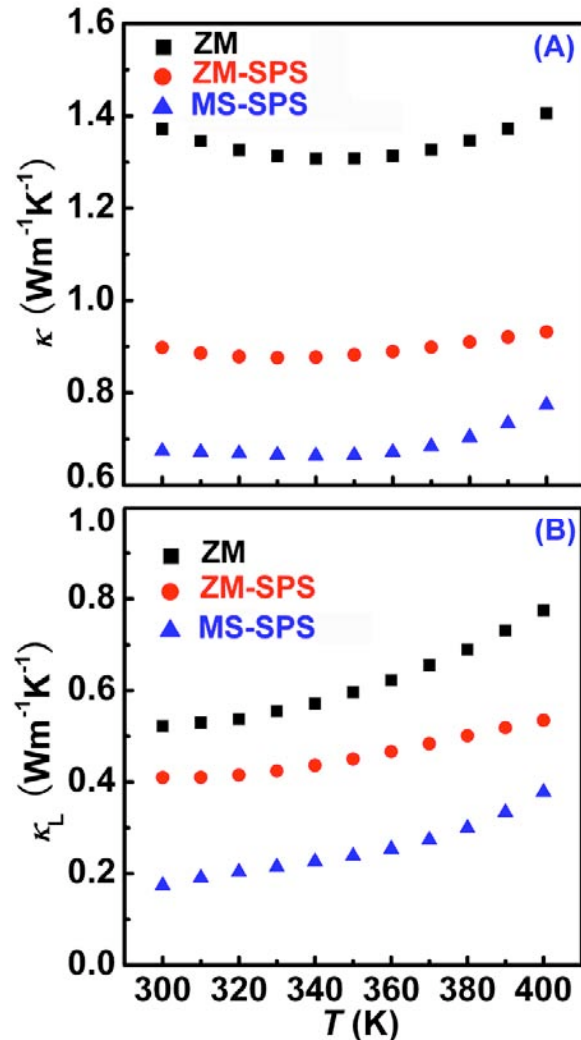
Spark Plasma Sintering System: 1500 Amps



Sample
In Mold



TE Properties of Melt Spun p-type $\text{Bi}_{0.52}\text{Sb}_{1.48}\text{Te}_3$



But the **MS-SPS Sample**
Exhibited lower κ_L and thus
Higher ZT ($ZT \approx 1.5$)
Than other samples

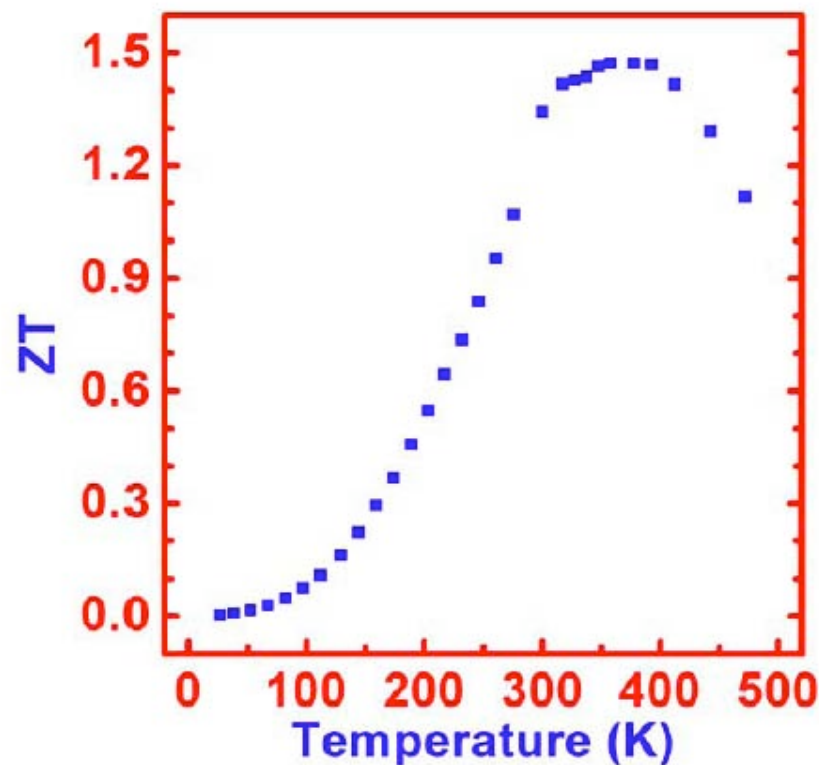
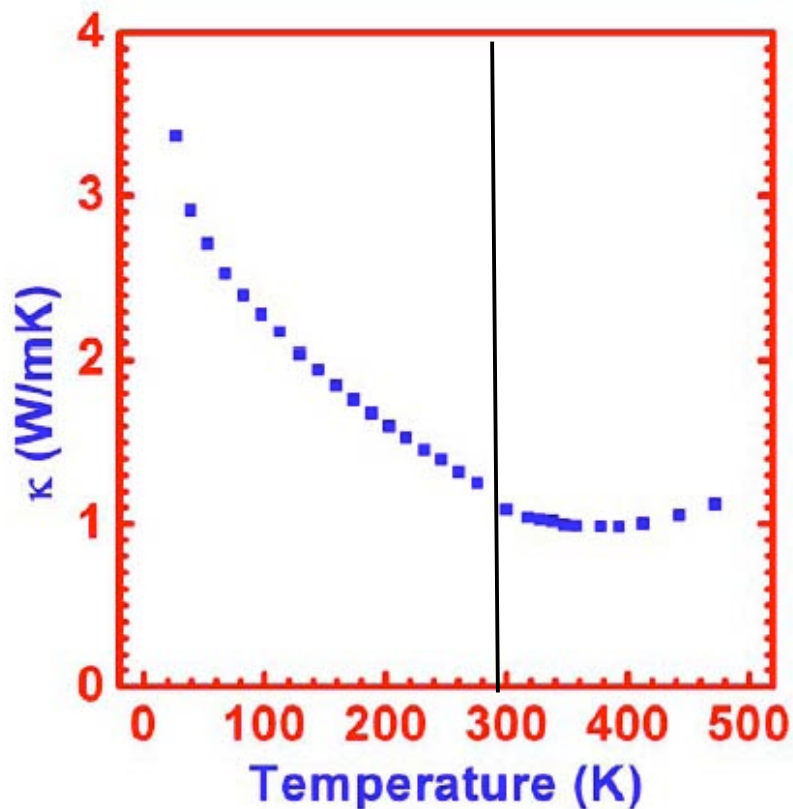
Collaboration w. Prof. X. Tang and student Wenjie Xie
Wuhan Univ. of Tech:
W.Xie *et.al*, Applied Phys Letters, **94**, 102111-2009

Low Temperature ($T < 300\text{K}$) Properties of MS-SPS -- Bi_2Te_3

Low Temperature (κ) by Steady State Technique

(see Cryogenics- Pope et.al 2000)

High Temp. Using (κ) Laser Flash and DSC



Concluding Remarks

- Increased Demands for Alternative Energy Systems
- Significant Progress in TE's in Last 10 Years
- Thermoelectrics: (Shift to Waste Heat Recovery)
Efficiency & **Stability** is a Materials Issue.
- Thermoelectric Materials Research:
 - “Designer Materials” Approach
 - Complex Structures & Transport Properties
 - Challenges in Theory, Synthesis & Characterization
- Low Dimensional TE Materials - - High ZT
Due primarily to reductions in lattice thermal conductivity
- Many Opportunities in Nanocomposites, “Grain Surface Engineering” or Nanoscaled Bulk TE Materials **ZT $\approx$ 1.4**
or Nanocomposites (Future-Spark Plasma Sintering)
- More Theoretical Modeling & Insight Needed



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